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Jin et al.(10) **Pub. No.: US 2022/0368338 A1**(43) **Pub. Date: Nov. 17, 2022**(54) **ANALOG-TO-DIGITAL CONVERTER (ADC)
TESTING**(52) **U.S. Cl.**CPC **H03M 1/1014** (2013.01)(71) Applicant: **NXP B.V.**, Eindhoven (NL)

(57)

ABSTRACT(72) Inventors: **Xiankun Jin**, Austin, TX (US);
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An integrated circuit device includes a digital sine wave generator configured to produce portions of a digital sine wave, a combiner circuit configured to output each of the portions of the digital sine wave combined with a respective calibration code during operation in a post-production dynamic test mode, a digital to analog converter (DAC) configured to output an analog sine wave based on the output of the combiner circuit, and a test analog to digital converter (ADC) including an input terminal directly connected to the output of the DAC, and configured to generate a second digital sine wave based on the analog sine wave.

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